

IRFM214B-VB Datasheet N-Channel 250 V (D-S) MOSFET

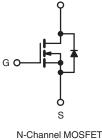
PRODUCT SUMMA	RY	
V _{DS} (V)	250)
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	2.0
Q _g (Max.) (nC)	8.2	
Q _{gs} (nC)	1.8	
Q _{gd} (nC)	4.5	
Configuration	Sing	le

FEATURES

- Surface mount
- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- · Fast switching
- Ease of paralleling
- Simple drive requirements







PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	250	v		
Gate-Source Voltage		V _{GS}	± 20			
Continuous Drain Current	$V_{GS} \text{ at } 10 \text{ V} \qquad \frac{T_C = 25 \text{ °C}}{T_C = 100 \text{ °C}}$	I	0.79			
Continuous Drain Current		T _C = 100 °C	ID	0.50	А	
Pulsed Drain Current ^a		I _{DM}	6.3			
Linear Derating Factor			0.025	W/°C		
Linear Derating Factor (PCB Mount) ^e			1	0.017	VV/ C	
Single Pulse Avalanche Energy ^b			E _{AS}	50	mJ	
Repetitive Avalanche Current ^a			I _{AR}	0.79	А	
Repetitive Avalanche Energy ^a			E _{AR}	0.31	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$			3.1	14/		
Maximum Power Dissipation (PCB Mount) e	T _A = 25 °C		PD	2.0	W	
Peak Diode Recovery dV/dt ^c		dV/dt	4.8	V/ns		
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	**	
Soldering Recommendations (Peak Temperature) ^d	for 1	0 s		300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 128 mH, $R_g = 25 \Omega$, $I_{AS} = 0.79 \text{ A}$ (see fig. 12). c. $I_{SD} \le 2.7 \text{ A}$, dl/dt $\le 65 \text{ A/}\mu$ s, $V_{DD} \le V_{DS}$, $T_J \le 150 \text{ °C}$.

d. 1.6 mm from case.

e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RAT	INGS				
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	60	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	40	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	250	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.39	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20 V$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	-	= 250 V, V _{GS} = 0 V /, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 0.47 A ^b	_	2.0	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	50 V, I _D = 0.47 A	0.50	-	-	S
Dynamic							1
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	140	-	
Output Capacitance	C _{oss}			-	42	-	pF
Reverse Transfer Capacitance	C _{rss}			-	9.6	-	
Total Gate Charge	Qg			-	-	8.2	
Gate-Source Charge	Q _{qs}	V _{GS} = 10 V	I _D = 2.7 A, V _{DS} = 200 V, see fig. 6 and 13 ^b	-	-	1.8	nC
Gate-Drain Charge	Q _{qd}		see lig. 0 and 15 °	-	-	4.5	
Turn-On Delay Time	t _{d(on)}		•	-	7.0	-	
Rise Time	t _r	- V _{DD} =	125 V, I _D = 2.7 A,	-	7.6	-	
Turn-Off Delay Time	t _{d(off)}	$R_g = 24 \Omega$, $R_D = 45 \Omega$, see fig. 10 ^b		-	16	-	- ns
Fall Time	t _f			-	7.0	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	
Internal Source Inductance	L _S			-	6.0	-	nH
Drain-Source Body Diode Characteristic	s	<u>.</u>					
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol		-	0.79	
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction		-	-	6.3	A
Body Diode Voltage	V_{SD}	T _J = 25 °C,	$I_{\rm S}$ = 0.79 A, $V_{\rm GS}$ = 0 V ^b	-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	T 05 %0 1	070 -11/-14 1000/-b	-	190	390	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_{\rm J} = 25 \ ^{\circ}{\rm C}, I_{\rm F} = 2.7 \ {\rm A}, \ {\rm d}{\rm I}/{\rm dt} = 100 \ {\rm A}/\mu {\rm s}^{\rm b}$		-	0.64	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	-on is dor	ninated b	v Ls and	Ln)	

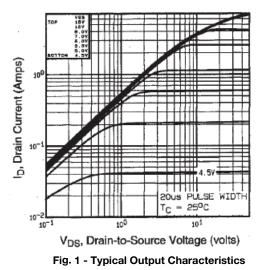
Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300~\mu s;~duty~cycle \leq 2~\%.$



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



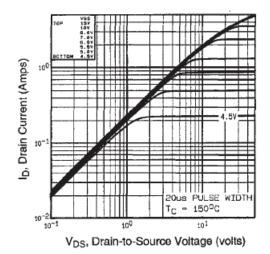


Fig. 2 - Typical Output Characteristics

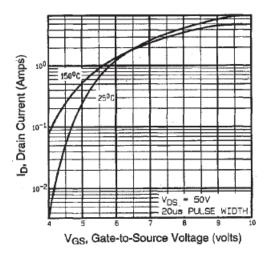


Fig. 3 - Typical Transfer Characteristics

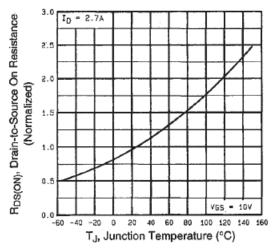


Fig. 4 - Normalized On-Resistance vs. Temperature

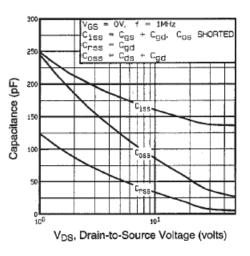


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

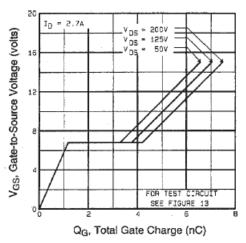


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



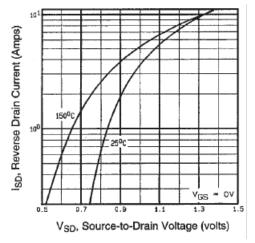


Fig. 7 - Typical Source-Drain Diode Forward Voltage

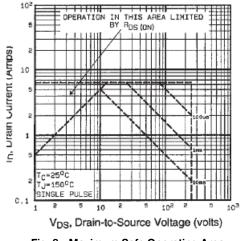


Fig. 8 - Maximum Safe Operating Area

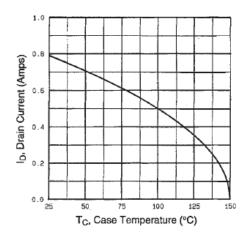


Fig. 9 - Maximum Drain Current vs. Case Temperature

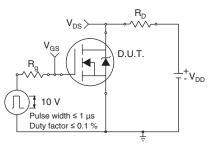


Fig. 10a - Switching Time Test Circuit

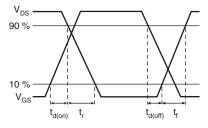


Fig. 10b - Switching Time Waveforms

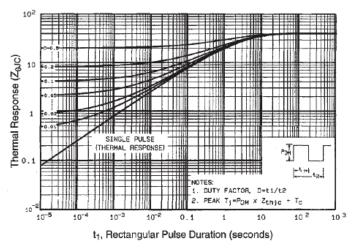


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



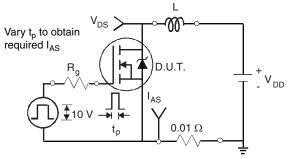


Fig. 12a - Unclamped Inductive Test Circuit

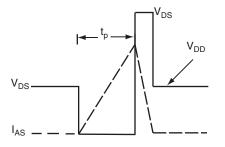


Fig. 12b - Unclamped Inductive Waveforms

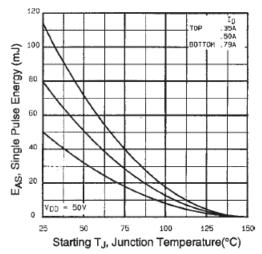


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

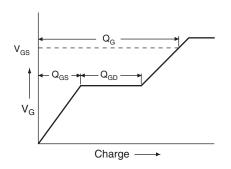


Fig. 13a - Basic Gate Charge Waveform

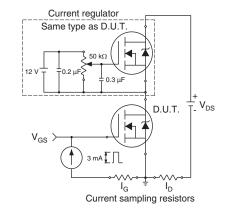
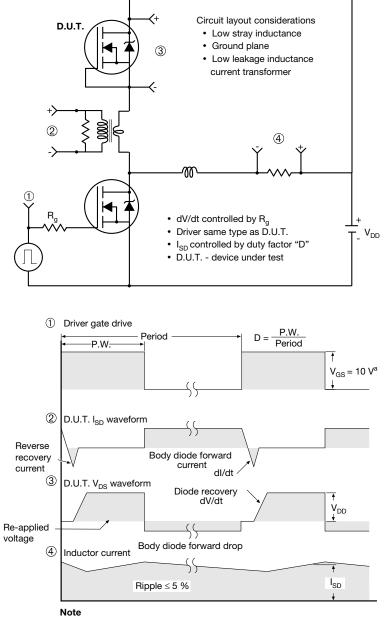


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

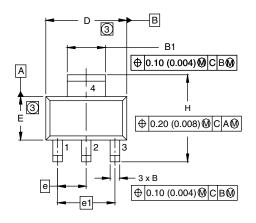


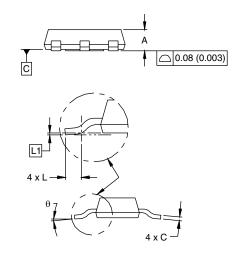
a. V_{GS} = 5 V for logic level devices

Fig.14 - For N-Channel



SOT-223 (HIGH VOLTAGE)





DIM.	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
E	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181 BSC		
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.002	4 BSC	
θ	-	10'	-	10'	

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

3. Dimension do not include mold flash.

4. Outline conforms to JEDEC outline TO-261AA.



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